

DREEBIT-Electron Beam Ion Sources and Traps

for Applications in Accelerator Physics

Speaker:

Mike Schmidt

*DREEBIT GmbH
and
Dresden University of Technology*



Why Highly Charged Ions

Properties, Production, Sources of HCI

EBIS/T Short History

Selected Milestones

DREEBIT Ion Sources

Room Temperature and Superconducting Ion Sources

Product Portfolio

Ion Beam Optics and Diagnostics

Applications

Charge Breeding and Medical Particle Therapy

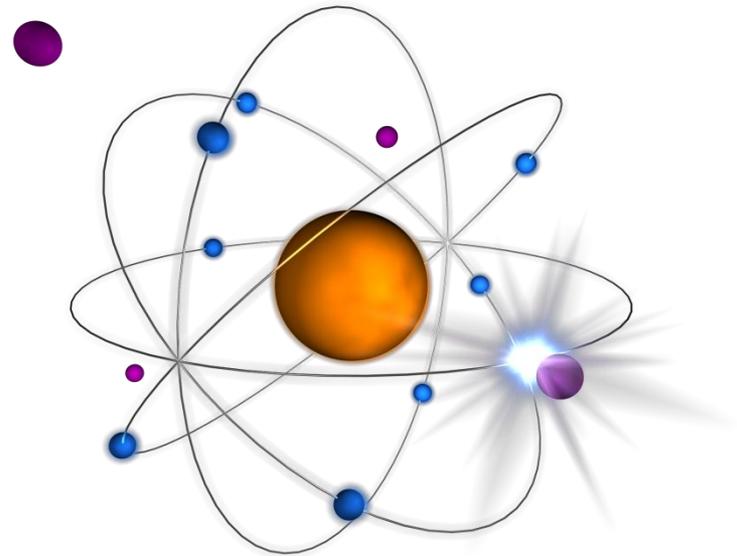
References

National and International Customer-specific Irradiation Facilities

Resumé

Why Highly Charged Ions ?

Properties of highly charged ions



Properties of Highly Charged Ions

Extremely Compact Accelerator Structures are possible

Due to their high charge q ions can be accelerated very effectively

- $\sim q$ for electrostatic accelerators
- $\sim q^2$ for circular accelerators

Example:

Xe¹⁺ and Xe⁴⁴⁺ acceleration at $\Delta U = 20$ kV



$\Delta U = 20$ kV

electrostatic accelerator

circular accelerator

Xe¹⁺

20 keV

20 keV

Xe⁴⁴⁺

880 keV

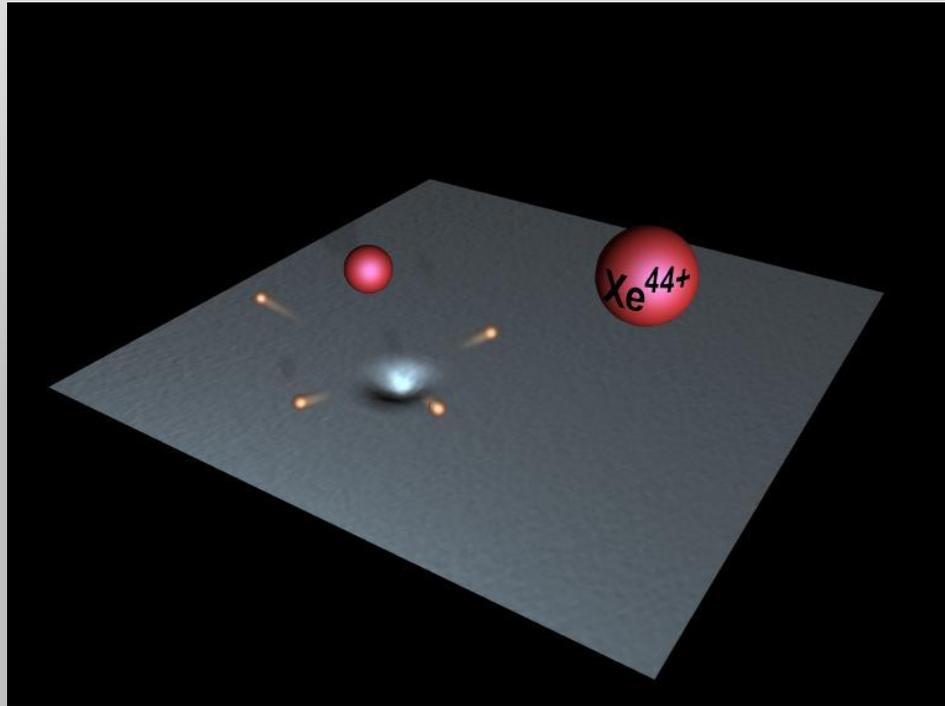
38720 keV = 38,72 MeV

(energy gain about factor 2000!)

Properties of Highly Charged Ions

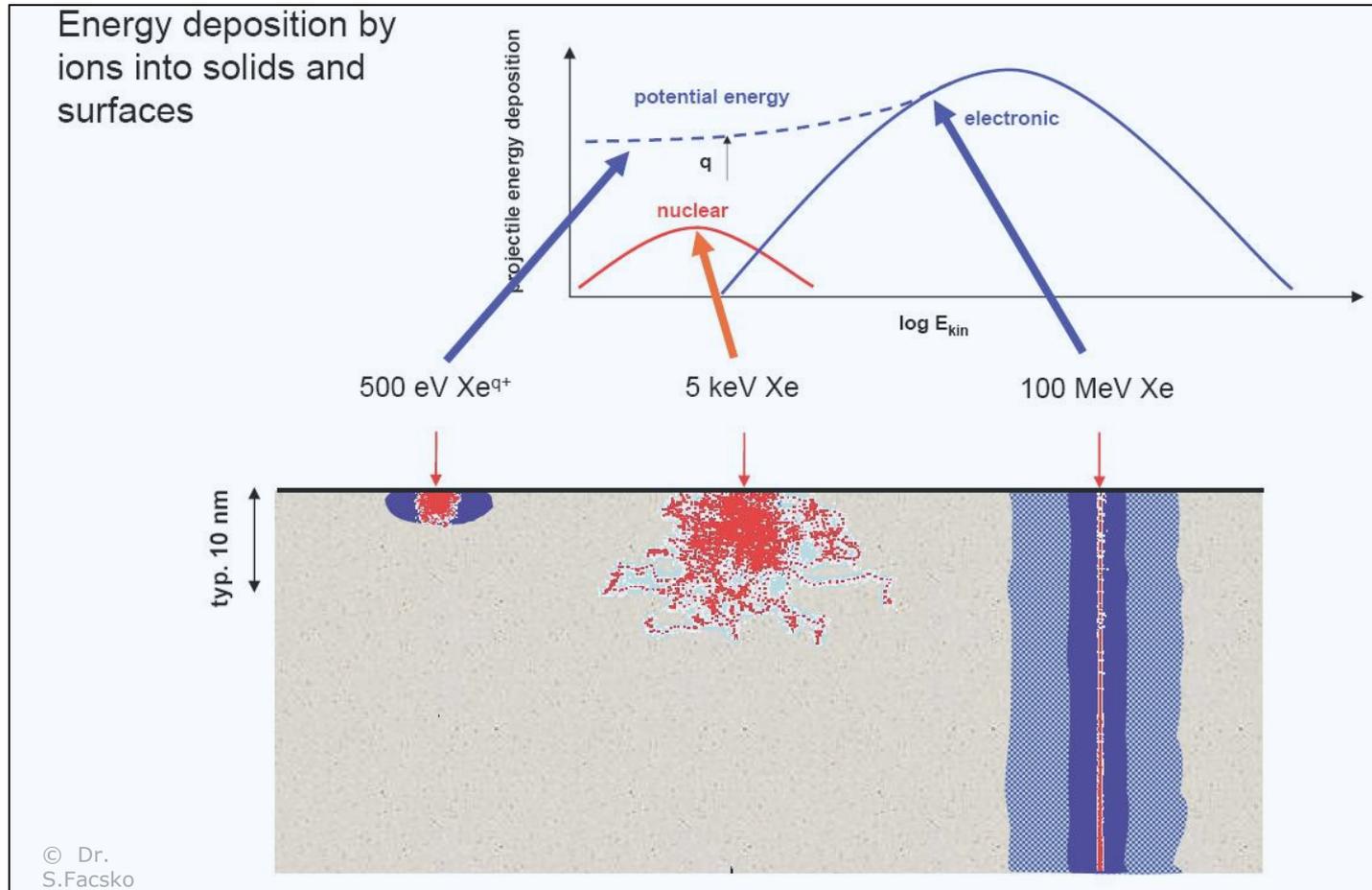
High power Deposition into Surfaces

The deposition of potential energy leads to ultrafast intense electronic excitations. Energy density: **$10^{12} \dots 10^{14} \text{ W/cm}^2$**



Properties of Highly Charged Ions

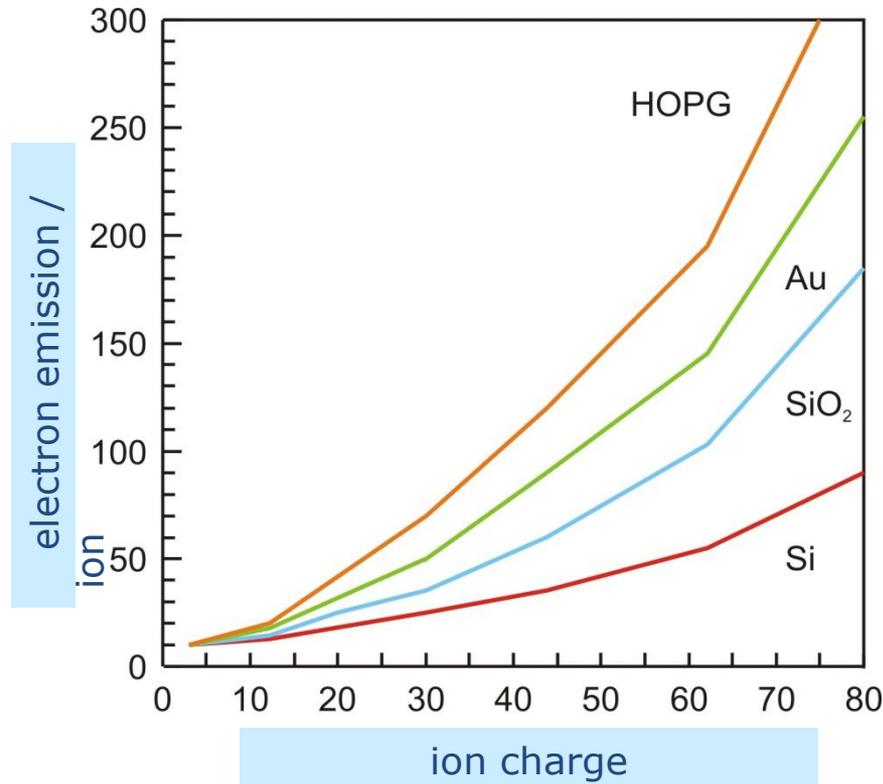
Energy Deposition into Surfaces



Properties of Highly Charged Ions

HCI give higher Yields of Secondary Ions and Electrons

J.W.McDonald et al: NIM B 240, 829 (2005)



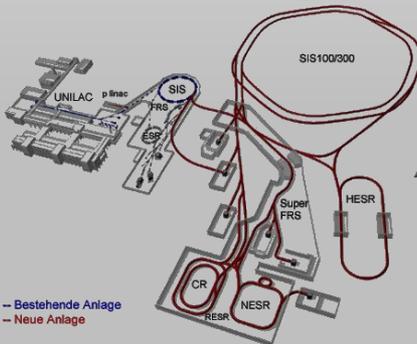
Total
electron
yields
vs ion
charge
state q

How to Produce Highly Charged Ions?

Ion Accelerators (GSI, TSR HD)

Stripping

- Up to bare nuclei at high projectile energies



up to U^{92+}

ECR Ion Sources

Electron Cyclotron Resonance (ECR)

- Heating of a magnetically confined plasma



Ar^{16+} , Ta^{38+} , Au^{41+}

Electron Beam Ion Sources/Traps

- Ionization in high-dense electron beams

- Electron beam compression in strong magnetic fields

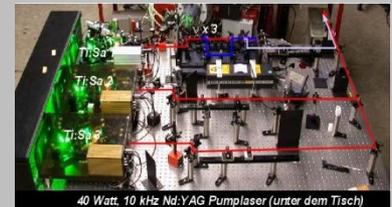
- Superconducting or permanent magnets



up to small amounts of U^{92+}

Laser Ion Sources

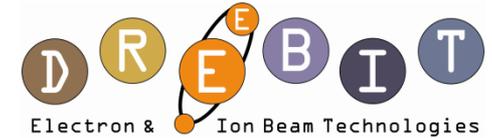
- Pulsed laser irradiation of selected targets



Pb^{27+} etc.

EBIS/T – Short History

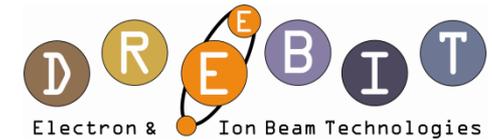
Selected Milestones



Year	Place/ Name	Device	Ions	Source type (B, trap length)
1968	Dubna (USSR) Donets	IEL I, IEL II	Au ¹⁹⁺	warm EBIS 0.4 T, 16 cm
1971	Dubna (USSR) Donets/Pikin	KRION I	C ⁶⁺ , N ⁷⁺ , O ⁸⁺ , Ne ¹⁰⁺	SC 1.2 T, 1.2 m
1974	Dubna (USSR) Ovsyannikov/Do nets	KRION 2	Ar ¹⁸⁺ , Kr ³⁶⁺ , Xe ⁵⁴⁺	SC 2.2 T, 1.2 m
1981 1986	Orsay (France) Arianer	CRYEBIS 1 CRYEBIS 2	C ⁶⁺ , N ⁷⁺ , Ne ¹⁰⁺ , Ar ¹⁸⁺	SC, 3 T, 1.66 m SC, 5 T, 1.66 m
1984	Saclay (France) Faure	DIONE	Ar ¹⁶⁺ , Kr ³⁰⁺ , I ⁴¹⁺	SC, 6 T, 1.2 m

EBIS/T – Short History

Selected Milestones



Year	Place/Name	Device	Ions	Source type (B, trap length)
1988 1990	LLNL (USA) Levine Marrs/Knapp	EBIT-I EBIT-II (birth of EBIT!)	Xe ⁵⁴⁺ , U ⁸⁸⁺	SC, 3 T, 2 cm (E _(e,max) = 29 keV)
1990	LLNL (USA) Marrs/ Schneider	S-EBIT	U ⁹²⁺ , Cf ⁹⁶⁺	SC, 3 T, 2 cm (E _(e,max) = 215 keV)
1999	Freiburg (Germany) Crespo	F/HD-EBIT	Xe ⁵⁴⁺	SC, 9 T, 4-30 cm
2009	Brookhaven (USA) Beebe/Pikin	RHIC-EBIS	Xe ³⁶⁺ high current EBIS	SC 6 T, 1.5 m

EBIS/T – Short History

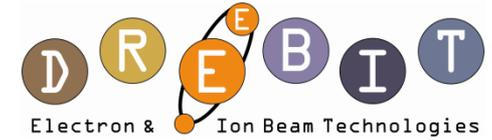
Selected Milestones



Year	Place/ Name	Device	Ions	Source type (B, trap length)
1999	TU Dresden (Germany) Ovsyannikov/ Zschornack	Dresden EBIT	Ar ¹⁸⁺ , Xe ⁴⁴⁺ , Ir ⁶⁷⁺	warm EBIT 0.25 T, 2 cm (E _(e,max) = 15 keV)
2005 2008	Dreebit GmbH (Germany) Ovsyannikov/ Zschornack	Dresden EBIS Dresden EBIS-A	Ar ¹⁸⁺ , Xe ⁴⁸⁺ , Ir ⁶⁷⁺	warm EBIS, 0.4/0.6 T, 6 cm (E _(e,max) = 25 keV)
2009	Dreebit GmbH (Germany) Ovsyannikov/ Zschornack	Dresden EBIS-SC (medical applications and R&D)	C ⁶⁺ , Ar ¹⁸⁺ , Xe ⁴⁸⁺	SC, 6 T, 4-30 cm (E _(e,max) = 20 keV)

EBIS/T – Short History

Selected Milestones



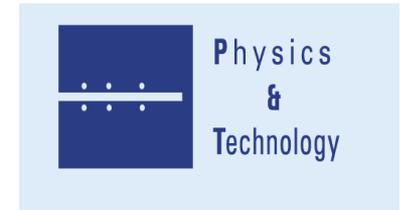
There are actually about 60 EBIS/EBIT around the world.
(For a list see R.Becker, O.Kester; RSI 81(2010) 02A513)

Most of them are special laboratory constructions.

Two commercial supplier worldwide:

1. Physics and Technology Livermore (USA)

REBIT (Refrigerated Electron Beam Ion Trap)



2. DREEBIT GmbH Dresden (Germany)

Dresden EBIT } Room-Temperature
Dresden EBIS } EBIS/T

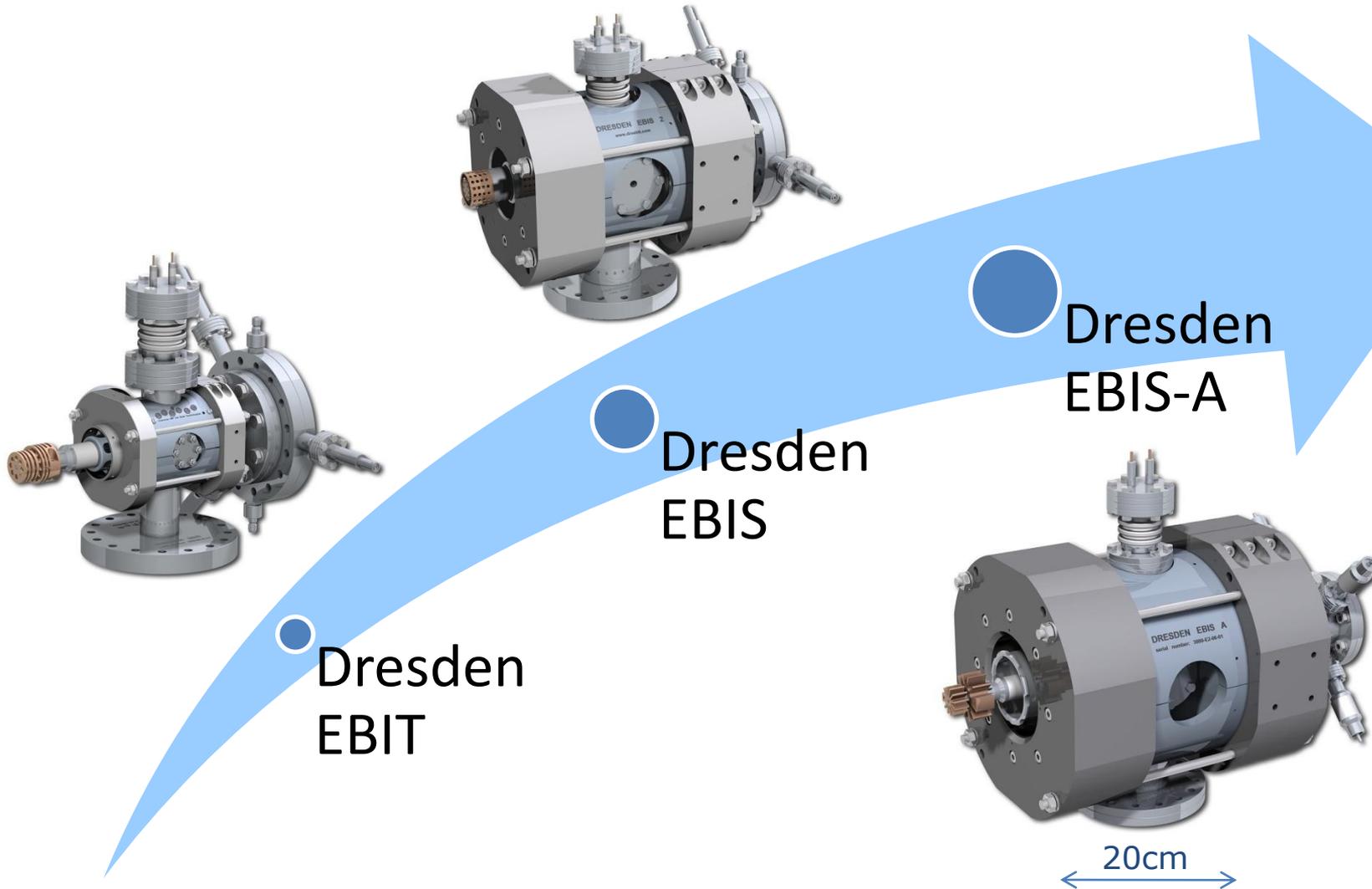
Dresden EBIS-A
Dresden EBIS-SC

(Refrigerated Electron Beam Ion Trap)



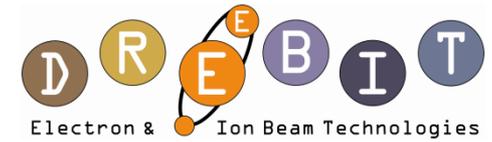
Room Temperature EBIS/T

DREEBIT Ion Sources



Dresden EBIS-SC (superconducting)

DREEBIT Ion Sources



↔
20cm



Measured ion pulses

Ion	Max. ions/pulse	Max. pulse rate/Hz
H ⁺	3·10 ⁹	500
H ₂ ⁺	3·10 ⁹	1000
C ⁴⁺	8·10 ⁸	10
C ⁶⁺	4·10 ⁸	10
Ar ¹⁶⁺	2·10 ⁷	2
I ⁴³⁺	1·10 ⁶	1

- L-He free at 4.2K
- electron beam energy up to 30 keV
- electron beam current up to 700 mA
- magnetic field on-axis 6T

Ion Source Output

DREEBIT Ion Sources



Pulsed mode (ions/pulse)

Ion	EBIT	EBIS-A	EBIS-SC	EBIT:EBIS-A:EBIS-SC
C⁴⁺	24.000.000	80.000.000	900.000.000	1 : 3 : 38
C⁶⁺	10.000.000	30.000.000	400.000.000	1 : 3 : 40
Ar¹⁶⁺	900.000	7.800.000	250.000.000	1 : 9 : 278
Ar¹⁷⁺	45.000	1.400.000	22.000.000	1 : 31 : 489
Ar¹⁸⁺	6.000	90.000	1.500.000	1 : 15 : 250
Xe⁴⁴⁺	10.000	700.000	10.000.000	1 : 70 : 1000

Ion Optics and Diagnostics

DREEBIT Product Portfolio

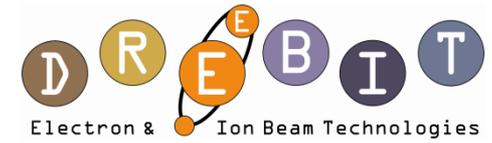


- Einzel lense
- Deflector
- Ion beam deceleration/acceleration system
- ExB Particle separator (Wien Filter)
- Faraday Cup
- Quadrupole Beam Bender
- Retarding Field Analyzer
- Pepperpot Emittance Meter...

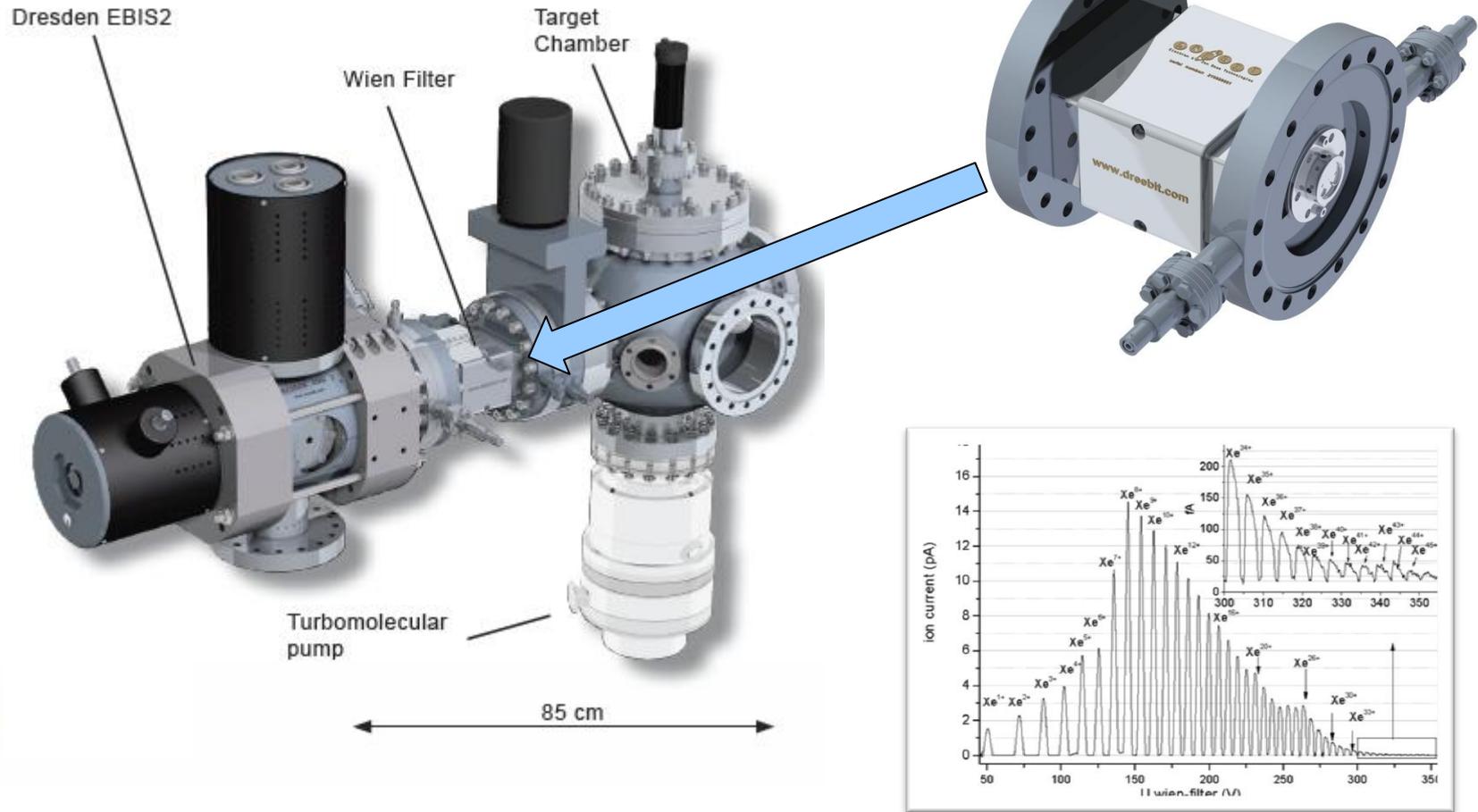


Ion Beam Diagnostics

DREEBIT Product Portfolio



q/A Analysis with a Wien filter



Ion Irradiation Facilities

DREEBIT Product Portfolio



Ion Irradiation Facility S



Ion Irradiation Facility L

Ion Irradiation Facilities

DREEBIT Product Portfolio

Equipment:

- Beamline positioning units
- Signal interface units
- Power and vacuum control unit
- High voltage terminal shielding

High voltage power supplies

Ion deceleration lens system

Large target chamber,
customer specifications
on request

Transfer chamber

Ion beam diagnostics:
Faraday cups, MCP
detector on request

Ion Irradiation
Facility L

Cat.No.: 10001

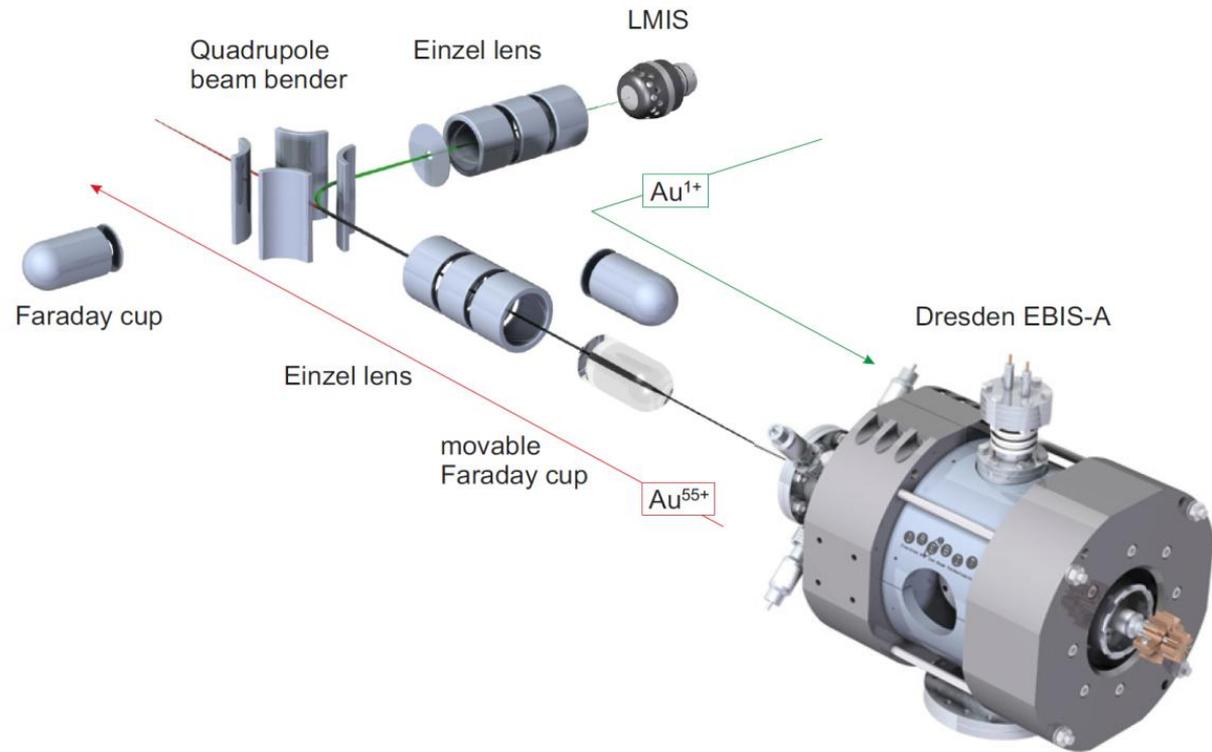
Mass separation: double
focusing analyzing dipole magnet

Dresden EBIS-A

Ion beam guiding
components: Einzel
lenses, ion deflectors

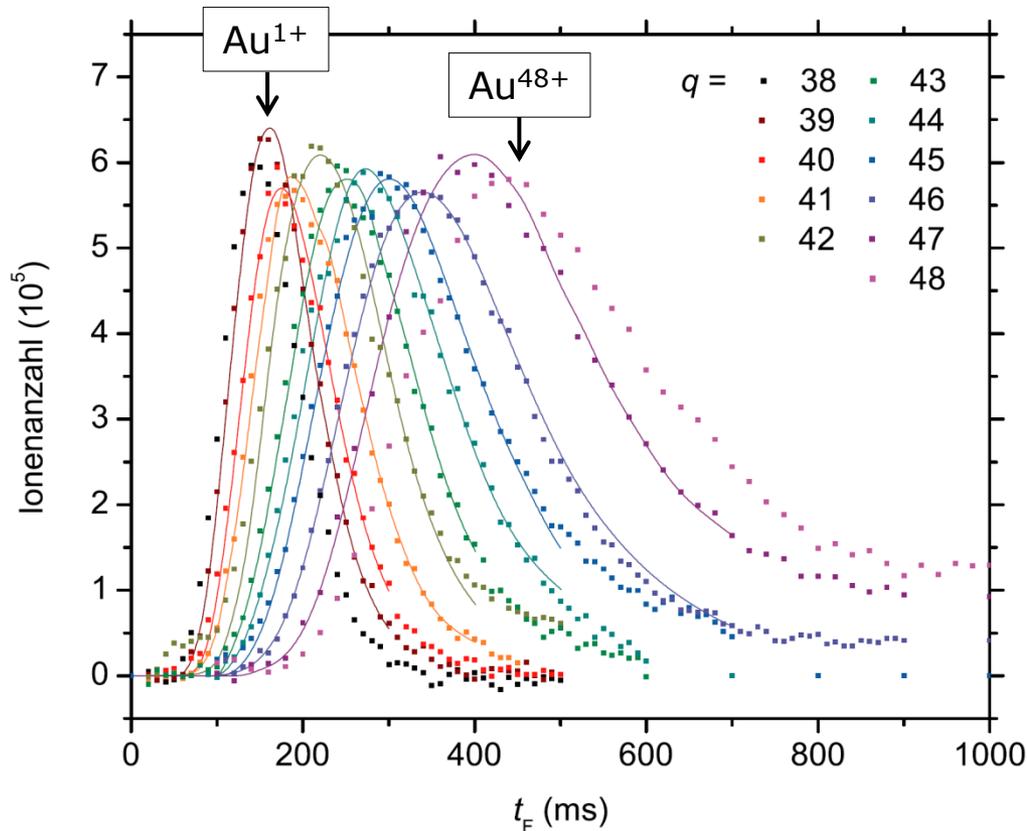
1 m

Charge Breeding



Applications

Charge Breeding: Gold



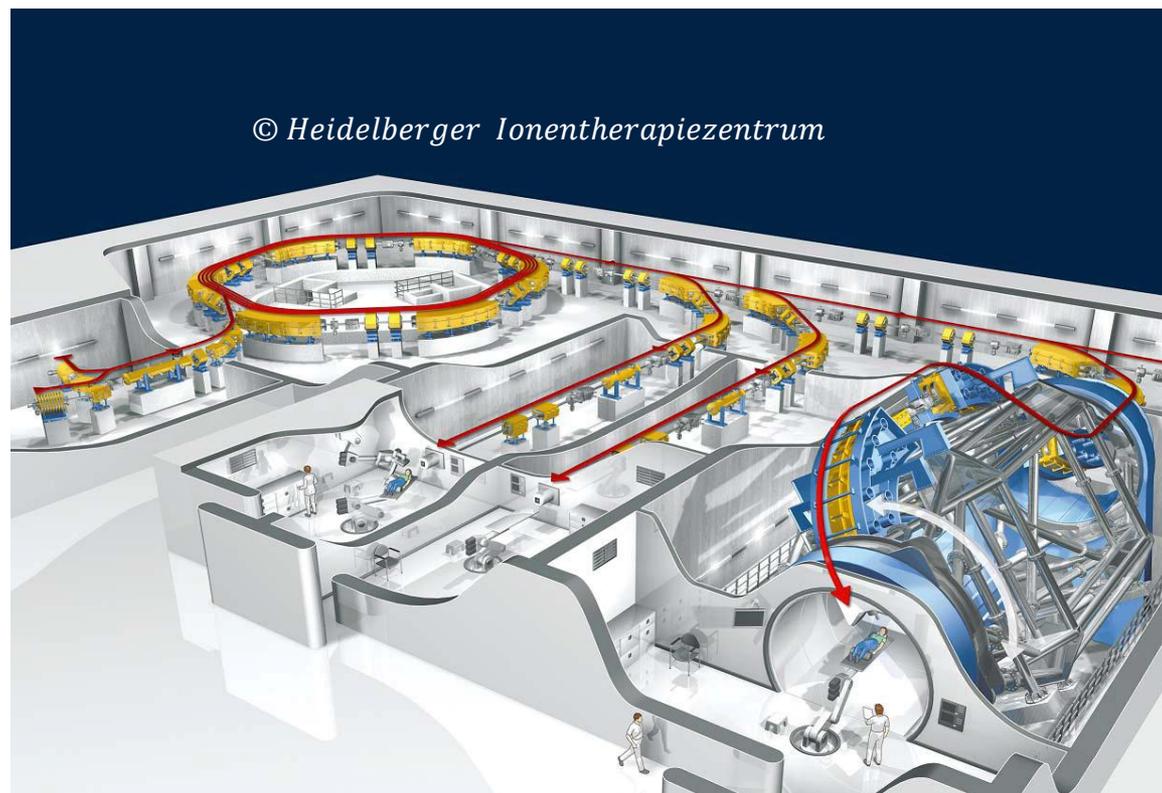
q/A analysis

→ Evolution of the ion charge states Au^{38+} to Au^{48+}

Description:

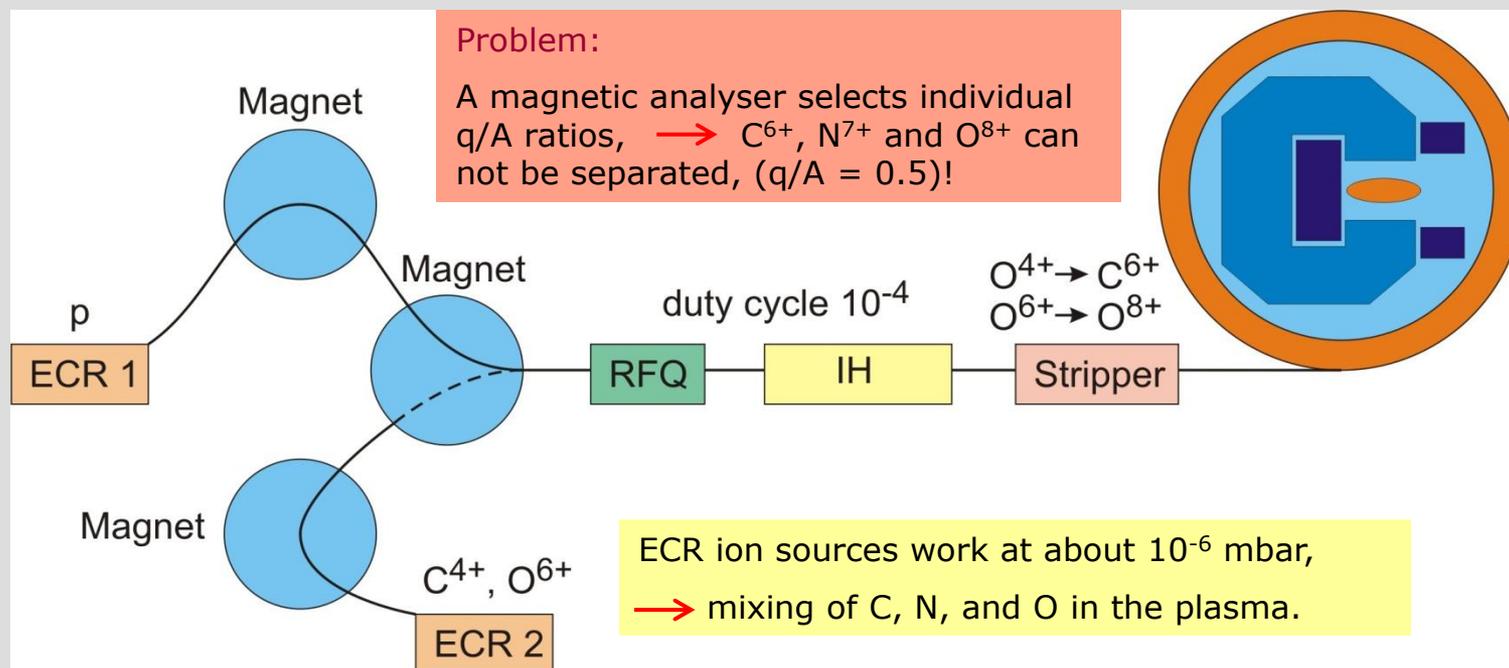
$$dN_{q+}/dt = \lambda_{q-1} \cdot N_{q-1} - \lambda_q \cdot N_q + \lambda_{q+1} \cdot N_{q+1}$$

Hadron Therapy



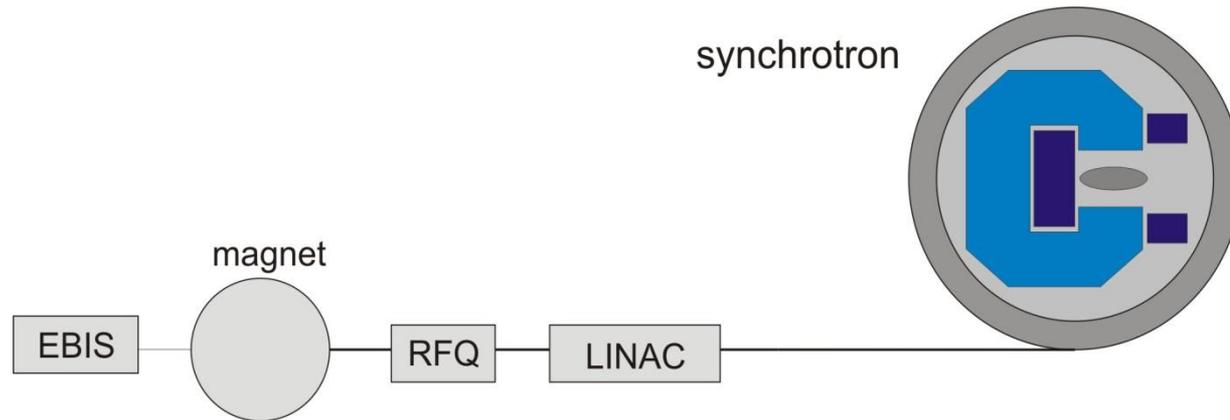
Basic Structure of a Synchrotron-based Irradiation Facility

Heidelberg Hadron Therapy Facility HIT:



R.Becker, ICIS-05 PA9/RSI MS # C05005

Simplification of Therapy Facilities by using an EBIS

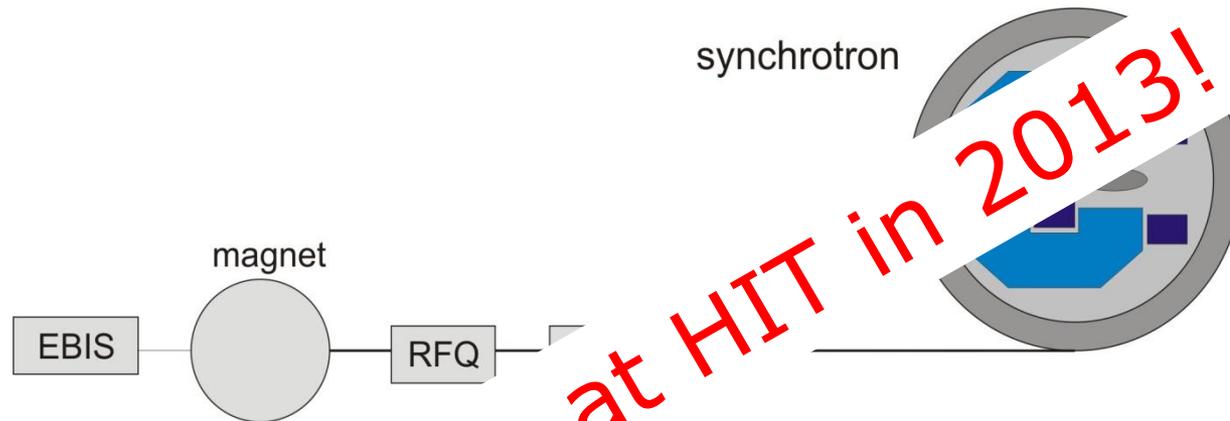


Advantages:

- only one ion source
- only one separation magnet
- shorter LINAC
- no stripper
- lower injection energy
- single-turn injection (at 4 MeV/u)
- smaller synchrotron magnets
- lower power consumption

**the complexity of the irradiation facility decreases,
the beam quality is improved,
costs can be reduced**

Simplification of Therapy Facilities by using an EBIS



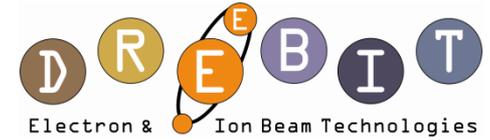
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DREEBIT Reference Facilities

Customer-specific Irradiation Facilities



SIEMENS



**TECHNISCHE
UNIVERSITÄT
DRESDEN**



Friedrich Schiller
University of Jena



Uniwersytet Jagielloński
Krakow



UNIVERSITÄT
DUISBURG
ESSEN

CLEMSON
UNIVERSITY

*The Jan Kochanowski
University of Humanities and Sciences*



Dresden EBIS/T systems have been successfully commissioned and operated at Low Energy Beamlines, but can also be used as ion sources for:

1. Cyclotrons
2. Synchrotrons
3. Synchro-Cyclotrons
4. Cyclotron Driven Linac
5. Dielectric Wall Accelerator
6. Direct Driven Accelerator
7. Fixed Field Alternating Gradient Accelerator

Thank you



Mike Schmidt

Dipl.-Phys.

R&D

DREEBIT GmbH

Zur Wetterwarte 50, Haus 301
01109 Dresden

Phone: +49 351 260 3526

Mobile: +49 174 3281 689

E-Mail: mike.schmidt@dreebit.com
<http://www.dreebit.com>

<http://www.dreebit.com>